

# Signal Integrity

Lecture 22  
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## Introduction

- Signal Integrity includes all IC design effects that cause the design to malfunction due to the distortion of the signal waveform:
  - Crosstalk (for delay and noise)
  - Power/Ground (P/G) integrity
    - IR-drop
    - Ldi/dt noise
    - LC resonances
  - Substrate coupling
  - Simultaneous switching noise

## Outline

- Crosstalk  $\leftarrow$
- Power/Ground (P/G) integrity
  - IR-drop
  - Ldi/dt noise
  - LC resonances
- Substrate coupling
- Simultaneous switching noise

**Impact of Signal Integrity**

1 in 5 Chips Fail Because of SI Today!

Source: Cadence International Research, Inc. 2001

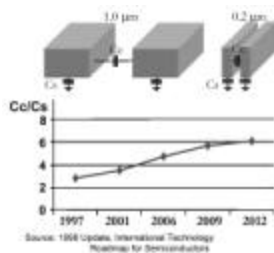
"Crosstalk due to coupling capacitance between adjacent interconnect lines, in 0.18 micron and below, has become a major performance limiting factor that can cause both noise injection and signal timing deviation."

- Bruno Franzini, STMicroelectronics, SNUG Europe 2001-

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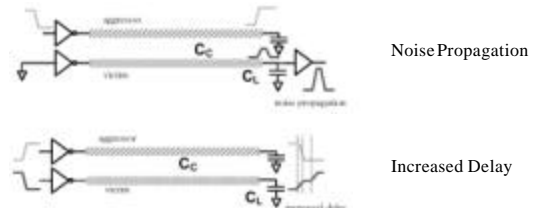
## Reminder on parasitics

Coupling capacitance dominates interlayer capacitance

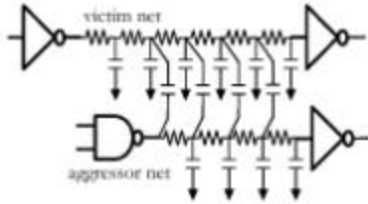


## Crosstalk

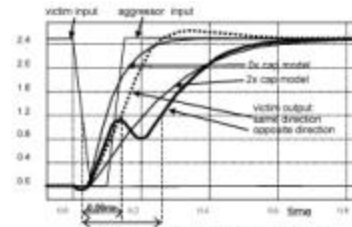
- Due to the coupling capacitance between interconnections, a signal switching on a net (aggressor) may affect the voltage waveform on a neighboring net (victim)



## Circuit Model for Crosstalk

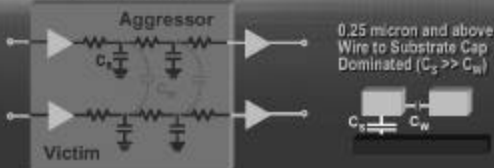


## Crosstalk Simulation



## Crosstalk Definition

### Gross-Coupled Capacitance



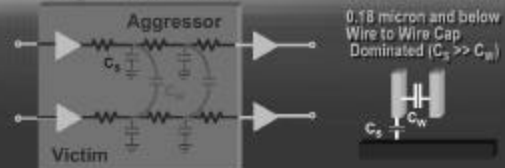
0.25 micron and above  
Wire to Substrate Cap  
Dominated ( $C_s \gg C_w$ )

- Static timing analysis tools model cross-coupling as grounded capacitors only

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## Crosstalk Definition

### Gross-Coupled Capacitance

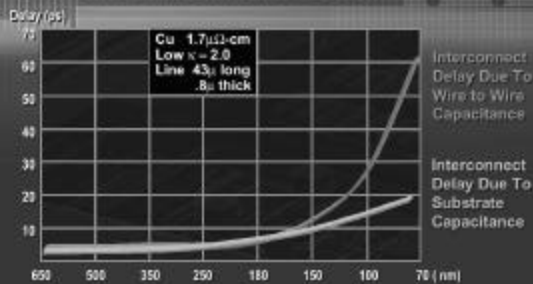


0.18 micron and below  
Wire to Wire Cap  
Dominated ( $C_c \gg C_w$ )



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## Crosstalk Is a 1<sup>st</sup>-Order Problem For 0.18 Micron and Below



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## Key Synopsys Advantages

### PrimeTime-SI

Static Timing Analysis

+

Static Crosstalk Analysis

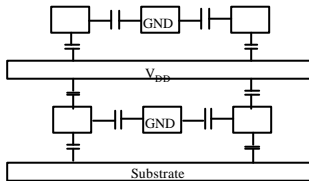
STA Technology with Crosstalk

- Based on proven STA technology
- Crosstalk analysis throughout the design process
- Integration with implementation flow
- Multi-million gate capacity and performance

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## Design for Crosstalk

- It can be both capacitive and inductive
  - Capacitive is dominant at current switching speeds
- To reduce it:
  - Use of shielding layer (inter-layer)
  - Use of shielding wire (intra-layer)



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## P/G Integrity

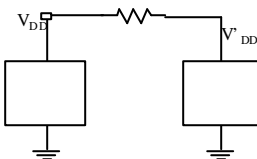
- Technology scaling imposes requirements on the reduction of power supply voltage
- Power/Ground integrity becomes a serious challenge during design
  - 10% supply voltage fluctuations may translate in more than 10% timing inaccuracy
  - Or even cause circuit to fail

## Outline

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## What is IR-drop?

- Increased resistance affects circuit operation:
    - Increased propagation delay
    - Resistive voltage drop (IR-drop)
- ⇒ Especially for Power Distribution Network



## What is IR-drop?

- IR-drop: voltage drop of the power and ground due to current flowing in the power/ground resistive network

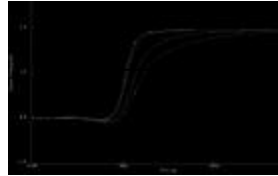


IR_drop	Delta%
0V	0.114ns
0.15V	0.126ns (+10%)
0.3V	0.143ns (+25%)
0.5V	0.184ns (+61%)

## IR-drop simulations



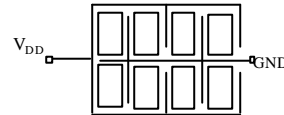
Voltage supply



Signal Waveform

## Power Distribution Network

- Most obvious solution: reduce max distance between supply pins and circuit supply connections
  - Finger-shaped power distribution network



## IR-drop consequences

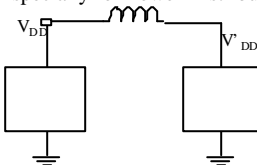
- Design and layout of power distribution network must be done early in the design process (then gradually refined)
- Design of the power network requires knowledge of the peak current (as opposed to power dissipation that relates to average current)  $\Rightarrow$  Reliability
- Delay is increased
- Noise Margins are reduced
- Technology scaling worsen the problem

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## What is Ldi/dt noise?

- Increased inductance affects circuit operation:
    - Delay behaves as transmission lines
    - Inductive coupling crosstalk
    - Inductive voltage drop (also called Delta-I noise)
    - It is a high-frequency phenomenon
- $\Rightarrow$  Especially for Power Distribution Network

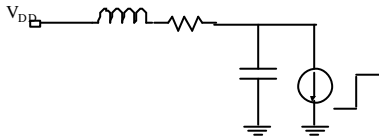


## Outline

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## What are LC resonances ?

- May impact the circuit also at low frequencies
- May not be localized (resonance waves may travel through the whole chip)

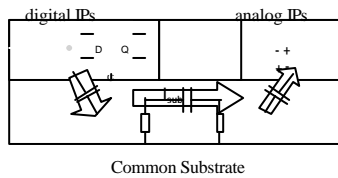


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## Substrate Coupling

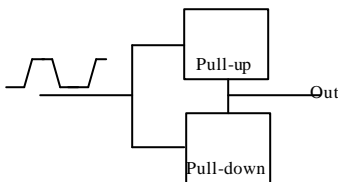
- Substrate is not equipotential
  - It has a (resistive) model
- There are substrate voltage variations that couples to blocks sharing the same substrate



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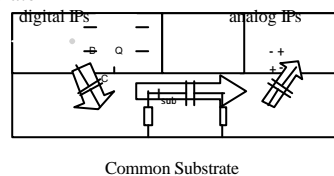
## Simultaneous Switching Noise (SSN)



- Strong dependence on input-pattern
- Injection even when output is not switching

## The Substrate Coupling Problem on Mixed-Signal Systems

- IPs can be safely re-used in mixed-signal system-on-a-chip designs only if they do not affect other critical components
- Digital components may inject considerable amount of **current noise** into analog components via the common substrate



## The Substrate Coupling Mechanisms: Need for Current Spectrum Estimation

Why substrate currents?

- Substrate potentials **may affect analog signals**:
  - though direct capacitive coupling
  - through variation of  $V_t$  (body effect)
- Digital IPs **inject current noise into the substrate** at clock frequency and its harmonics because of switching activity
- Substrate currents can easily reach analog IPs and change substrate potentials

Why frequency domain?

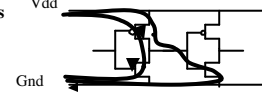
- Analog circuits are particularly sensitive in their frequency band of operation

**Need estimation of the maximum current injected by digital components for each harmonic of their clocks for safe operation!**

## The Timing Problem

- Digital components inject significant currents also into the power supply network:

- load charging currents
- short circuit currents

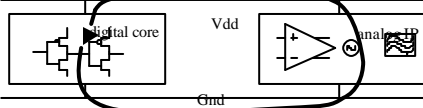


- IR drops may cause voltage variations and, consequently, **delay variations** within digital blocks.

**Need estimation of the instantaneous maximum current injected for delay analysis**

## The Signal Integrity Problem on the Power Supply Network

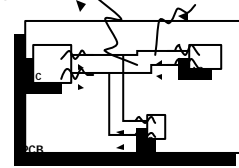
- Trend toward lower resistivity materials, e.g., copper  $\Rightarrow$  supply network becomes inductive and current noise may give **signal integrity** problems as in packages and PCBs:
  - Resonance with decoupling capacitors
  - Wavelength-related resonance (as frequency increases)
- Supply noise can easily **couple to the analog components** that share the same supply



**Need estimation of the maximum current at each frequency of the clock harmonics for signal integrity and supply coupling**

## Electromagnetic Interference Problem due to Digital Switching Activity

- High frequency currents created by digital ICs supply network can leak out to the package and PCB producing **electromagnetic interference emissions at the harmonics of the clock**



**Need estimation of maximum current at each frequency of the clock harmonics for EMI analysis**

## Estimation Techniques

### PROBLEMS

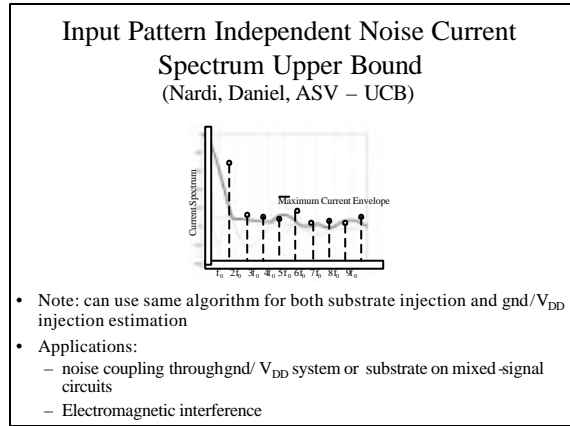
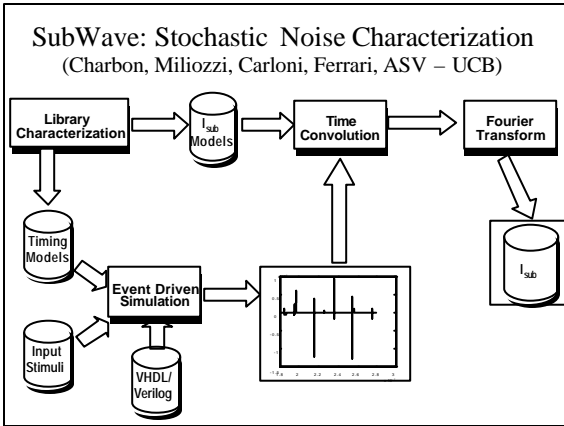
- Substrate coupling
- Timing
- Power consumption
- Supply coupling
- EMI

### REQUIREMENTS

- max substrate current at each harmonic
- max supply current instantaneous in time
- average supply current over many periods in time
- max supply current at each harmonic
- max supply current at each harmonic

## Some Approaches for Noise Current Estimation

- Vast literature on supply current estimation for power consumption: mainly concerned with average current in time [Najim TransVLSI94]
  - Most are based on switching activity estimation with propagation of probability distributions
- Some algorithms exist for maximum current envelope estimation instantaneously in time [Bobba ISPD98]. Mainly for timing problems, not suitable for substrate coupling, signal integrity and EMI.
- Stochastic approach for current estimation in the frequency domain
  - [Demir ICCAD99]: combines the approach from power analysis based on propagation of switching activity probabilities, with an estimation of frequency spectrum for substrate or signal integrity problems
  - [Charbon TransCAD99]
- Missing an approach for current upper bound estimation in the frequency domain



- ### Summary on Signal Integrity
- Crosstalk
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    - IR-drop
    - $Ldi/dt$  noise
    - LC resonances
  - Substrate coupling
  - Simultaneous switching noise